# MSKSEMI 美森科













ESD

TV

TSS

MOV

GDT

PIFD

S9012

Product specification





#### TRANSISTOR (PNP)

#### **FEATURES**

- High Collector Current
- Complementary To S9013
- Excellent hFE Linearity

#### **Reference News**

PACKAGE OUTLINE		MARKING	
1 2	1. BASE 2. EMITTER 3.COLLECTOR	2T1	
SOT-23			

MAXIMUM RATINGS (Ta=25℃ unless otherwise noted)

Symbol	Parameter	Value	Unit
V <sub>CBO</sub>	Collector-Base Voltage	-40	V
V <sub>CEO</sub>	Collector-Emitter Voltage	-25	V
V <sub>EBO</sub>	Emitter-Base Voltage	-5	V
<b>l</b> c	Collector Current	-500	mA
Pc	Collector Power Dissipation	300	mW
R <sub>. JA</sub>	Thermal Resistance From Junction To Ambient	416	°C/W
Tj	Junction Temperature	150	°C
T <sub>stg</sub>	Storage Temperature	-55~+150	°C

## **ELECTRICAL CHARACTERISTICS (Ta=25℃ unless otherwise specified)**

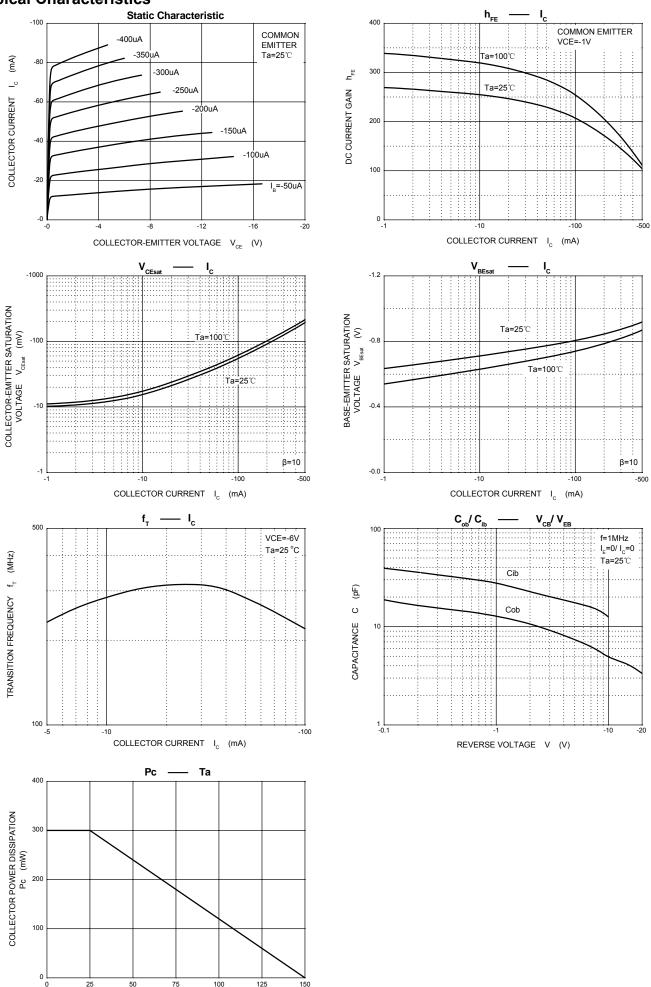
Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	$V_{(BR)CBO}$	I <sub>C</sub> =-0.1mA, I <sub>E</sub> =0	-40			V
Collector-emitter breakdown voltage	$V_{(BR)CEO}$	Ic=-1mA, I <sub>B</sub> =0	-25			V
Emitter-base breakdown voltage	V <sub>(BR)EBO</sub>	l <sub>E</sub> =-0.1mA, l <sub>C</sub> =0	-5			V
Collector cut-off current	Ісво	V <sub>CB</sub> =-40V, I <sub>E</sub> =0			-0.1	uA
Collector cut-off current	Iceo	V <sub>CE</sub> =-20V, I <sub>B</sub> =0			-0.1	uA
Emitter cut-off current	I <sub>EBO</sub>	V <sub>EB</sub> =-5V, I <sub>C</sub> =0			-0.1	uA
DC current gain	h <sub>FE</sub>	V <sub>CE</sub> =-1V, I <sub>C</sub> =-50mA	120		400	
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	I <sub>C</sub> =-500mA, I <sub>B</sub> =-50mA			-0.6	V
Base-emitter saturation voltage	V <sub>BE(sat)</sub>	I <sub>C</sub> =-500mA, I <sub>B</sub> =-50mA			-1.2	V
Transition frequency	f⊤	V <sub>CE</sub> =-6V,I <sub>C</sub> =-20mA, f=30MHz	150			MHz
Collector output capacitance	$C_ob$	V <sub>CB</sub> =-10V, I <sub>E</sub> =0, f=1MHz			5	pF

## **CLASSIFICATION OF hfE(1)**

RANK	L	Н	J
RANGE	120-200	200-350	300-400



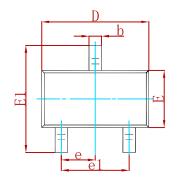
#### Typical Characteristics

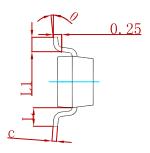


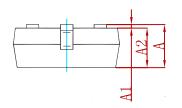
AMBIENT TEMPERATURE Ta (℃)



### PACKAGE MECHANICAL DATA

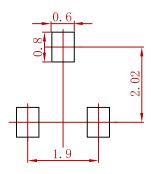






Cumbal	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
Е	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.03	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.02	2 REF	
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

## **Suggested Pad Layout**



#### Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

### **REEL SPECIFICATION**

P/N	PKG	QTY
S9012	SOT-23	3000



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